

JEOL Image Contest Winner - September 2016

Zinc Condensation Crystals

Zinc coating condensed onto piece of bare steel beneath it.
Credit: Joshua Solomon, General Motors; SEM: JSM-IT100

See all entries for [2016 Image Contest](#) or [submit an image](#).

New for 2016 - [Vote for your favorite](#)

Failure Analysis with the SEM

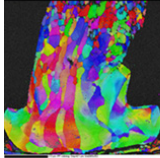
[See us at ISTFA](#)

November 8-9 - Fort Worth, Texas

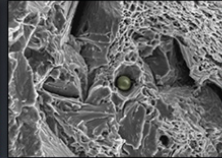
UNLOCK THE ANSWERS TO YOUR FAILURE ANALYSIS QUESTIONS

Solutions for Innovation

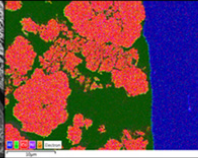
SMART FLEXIBLE POWERFUL IMAGING & ANALYSIS



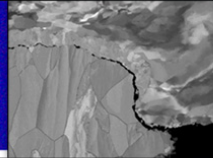
EDS - cross section of wire bond



Ductile and brittle fracture with an inclusion
Courtesy Sheri Neva, EAG



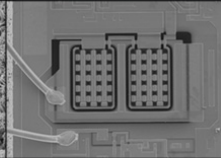
EDS - cross section of lithium battery



Fracture in wire bond



Rust

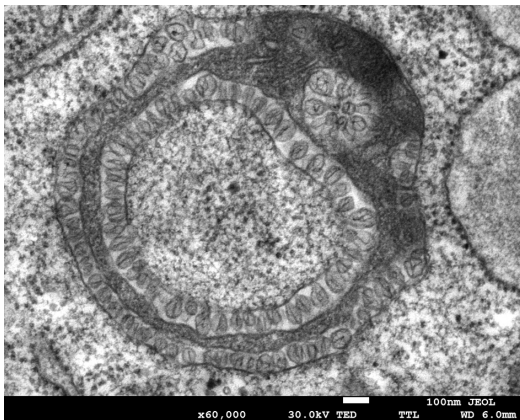


EBIC imaging - semiconductor device



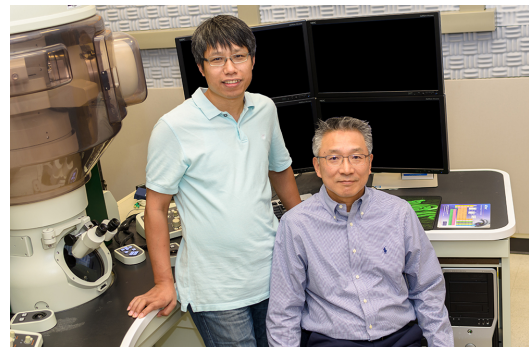
See us at
Booth #200!

[Learn more about our solutions](#) for failure analysis, including the [IT300 InTouchScope](#) high resolution analytical SEM, [NeoScope](#) benchtop SEM with EDS, [Cross Section Polisher](#) for sample prep.



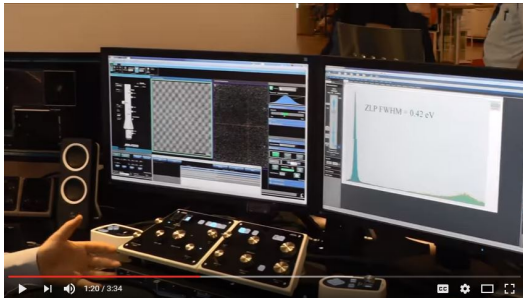
Tech Note: STEM-in-SEM

STEM-in-SEM (Scanning Transmission Electron Microscopy in an SEM) has become a popular technique for biologists, polymer scientists and materials scientists for its ease of use, cost effectiveness and high resolution. This "low voltage STEM" technique is ideal for life sciences as well as ultrathin sections of materials samples. Learn more about this technique in the [Technical Note](#).



UT Dallas Engineers Characterize a Novel Transistor

UT Dallas engineers and colleagues used ARM to characterize a novel transistor - one that is made with a new combination of materials that is even smaller than the smallest possible silicon-based transistor. Dr. Moon Kim, professor of materials science and engineering at UT Dallas and an author of the study, says, "Our research provides new insight into the feasibility to go beyond the ultimate scaling limit of silicon-based transistor technology." [More>](#)



[Video of a remote demo](#) of the new F2 analytical 200kV S/TEM with Cold FEG

Recently Published & In the News

The application of portable XRF and benchtop SEM-EDS to Cu-Pd exploration in the Coldwell Alkaline Complex, Ontario, Canada

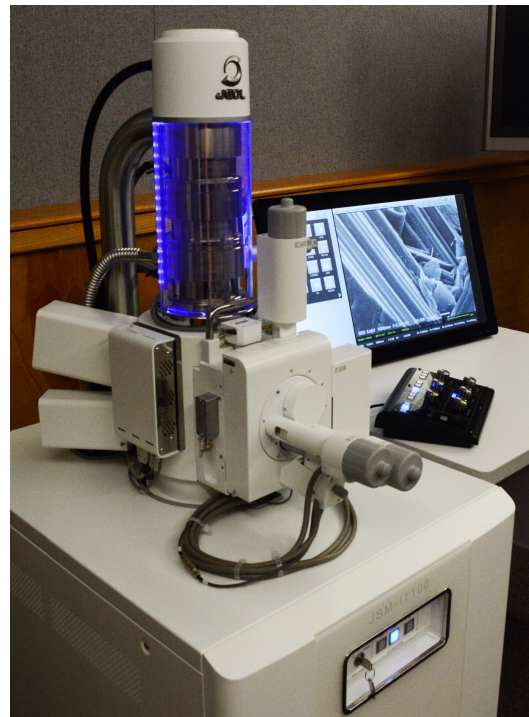
MoS₂ Transistors with 1 nanometer Gate Lengths

Inside Facebook's robotic inner sanctum: a tour of its highly secretive hardware lab

Surface faceting and elemental diffusion behaviour at atomic scale for alloy nanoparticles during in situ annealing

JEOL News Magazine 2016 can be downloaded from [our website](#) (registered users only), or ask us for a copy. Back issues are also available.

Share your publication news - send a link or pdf to jeolink@jeol.com.



New and Notable

LED lights on the column aren't just for show! The optional lighting kit for the [JSM-IT100](#) and [JSM-IT300](#) column InTouchScope changes color to indicate SEM status.

Check out our [upcoming events](#) including a Particle Analysis Seminar and Metals & Materials Mashup.

The 2017 [SEM training schedule](#) is now online.

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